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| 11 | IFORMATIO | N DIS | SCLOSURE | Filing Date | January 30, 2004 | |
| S | TATEMENT | BY A | PPLICANT | First Named Inventor | Franz Hofmann | |
| | | _ | | Art Unit | N/A 2875 | |
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| Sheet | 1 | of | 1 | Attorney Docket Number | 20046/0200815-US0 | |

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Complete if Known te for form 1449A/B/PTO Application Number 10/768,971 INFORMATION DISCLOSURE Filing Date January 30, 2004 STATEMENT BY APPLICANT First Named Inventor Franz Hofmann Art Unit (Use as many sheets as necessary) Not Yet Assigned WOO Examiner Name 20046/0200815-US0 1 Sheet Attomey Docket Number

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